

June 2012

FDMA3027PZ

Dual P-Channel PowerTrench® MOSFET -30 V, -3.3 A, 87 m Ω

Features

- Max $r_{DS(on)}$ = 87 m Ω at V_{GS} = -10 V, I_D = -3.3 A
- Max $r_{DS(on)}$ = 152 m Ω at V_{GS} = -4.5 V, I_D = -2.3 A
- HBM ESD protection level > 2 KV typical (Note 3)
- Low profile 0.8 mm maximum in the new package MicroFET 2x2 mm
- RoHS Compliant

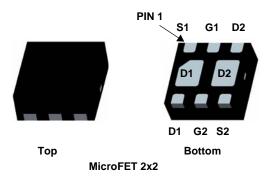
General Description

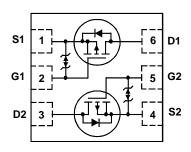
This device is designed specifically as a single package solution for dual switching requirements such as gate driver for larger Mosfets. It features two independent P-Channel MOSFETs with low on-state resistance for minimum conduction losses. The MicroFET 2x2 package offers exceptional thermal performance for its physical size and is well suited to linear mode applications. G-S zener has been added to enhance ESD voltage level.

Applications

- Load Switch
- Discrete Gate Driver







MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DS}	Drain to Source Voltage		-30	V
V_{GS}	Gate to Source Voltage		±25	V
ı	Drain Current -Continuous	(Note 1a)	-3.3	۸
'D	-Pulsed		-15	A
В	Power Dissipation	(Note 1a)	1.4	W
P_{D}	Power Dissipation	(Note 1b)	0.7	T VV
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

	Thermal Resistance for Single Operation, Junction to Ambient	(Note 1a)	86	
	Thermal Resistance for Single Operation, Junction to Ambient	(Note 1b)	173	
D	Thermal Resistance for Dual Operation, Junction to Ambient	(Note 1c)	69	°C/W
$R_{\theta JA}$	Thermal Resistance for Dual Operation, Junction to Ambient	(Note 1d)	151	C/VV
	Thermal Resistance for Single Operation, Junction to Ambient	(Note 1e)	160	
	Thermal Resistance for Dual Operation, Junction to Ambient	(Note 1f)	133	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
327	FDMA3027PZ	MicroFET 2X2	7 "	8 mm	3000 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, referenced to 25 °C		-22		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -24 V, V _{GS} = 0 V			-1	μА
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μА

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = -250 \mu A$	-1	-1.9	-3	٧
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = -250 μ A, referenced to 25 °C		5		mV/°C
		$V_{GS} = -10 \text{ V}, I_D = -3.3 \text{ A}$		69	87	
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -2.3 \text{ A}$		108	152	mΩ
		$V_{GS} = -10 \text{ V}, I_D = -3.3 \text{ A}, T_J = 125 \text{ °C}$		97	122	
9 _{FS}	Forward Transconductance	$V_{DS} = -5 \text{ V}, I_{D} = -3.3 \text{ A}$		6		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 45 V V 0 V	324	435	pF
Coss	Output Capacitance	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1 MHz	59	80	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 1/11/12	53	80	pF
R_q	Gate Resistance		12		Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time			5.2	11	ns
t _r	Rise Time	V_{DD} = -15 V, I_{D} = -3.3 A, V_{GS} = -10 V, R_{GEN} = 6 Ω		3	10	ns
t _{d(off)}	Turn-Off Delay Time			17	31	ns
t _f	Fall Time			11	25	ns
0	Total Gate Charge	$V_{GS} = 0 \text{ V to -10 V}$		7.2	10	nC
$Q_{g(TOT)}$	Total Gate Charge	$V_{GS} = 0 \text{ V to -5 V}$	V _{DD} = -15 V,	4.1	6	nC
Q_{gs}	Gate to Source Charge		$I_D = -3.3 \text{ A}$	1.0		nC
Q_{gd}	Gate to Drain "Miller" Charge			1.9		nC

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -3.3 \text{ A}$	(Note 2)	-0.94	-1.3	V
t _{rr}	Reverse Recovery Time	-I _E = -3.3 A, di/dt = 100 A/μs		20	32	ns
Q_{rr}	Reverse Recovery Charge	- 1 _F = -3.5 A, α/αι = 100 A/μs		10	18	nC

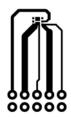
Electrical Characteristics T_J = 25 °C unless otherwise noted

Notes:

- 1. $R_{\theta JA}$ is determined with the device mounted on a 1 in² oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta JA}$ is determined by the user's board design.
 - (a) $R_{\theta,JA} = 86$ °C/W when mounted on a 1 in² pad of 2 oz copper, 1.5 " x 1.5 " x 0.062 " thick PCB. For single operation.
 - (b) $R_{\theta JA}$ = 173 °C/W when mounted on a minimum pad of 2 oz copper. For single operation.
 - (c) $R_{\theta,JA} = 69$ °C/W when mounted on a 1 in² pad of 2 oz copper, 1.5 " x 1.5 " x 0.062 " thick PCB. For dual operation.
 - (d) $\rm R_{\theta JA}$ = 151 $^{\rm o} \rm C/W$ when mounted on a minimum pad of 2 oz copper. For dual operation.
 - (e) $R_{\theta JA} = 160$ °C/W when mounted on a 30 mm² pad of 2 oz copper. For single operation.
 - (f) $R_{\theta JA} = 133$ °C/W when mounted on a 30 mm² pad of 2 oz copper. For dual operation.



a. 86 °C/W when mounted on a 1 in² pad of 2 oz copper



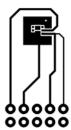
b. 173 °C/W when mounted on a minimum pad of 2 oz copper



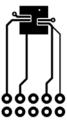
c. 69 °C/W when mounted on a 1 in² pad of 2 oz copper



d. 151 °C/W when mounted on a minimum pad of 2 oz copper



e. 160 °C/W when mounted on 30 mm² pad of 2 oz copper



f. 133 °C/W when mounted on 30 mm² pad of 2 oz copper

- 2. Pulse Test : Pulse Width < 300 us, Duty Cycle < 2.0%
- 3. The diode connected between gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

Typical Characteristics T_J = 25 °C unless otherwise noted

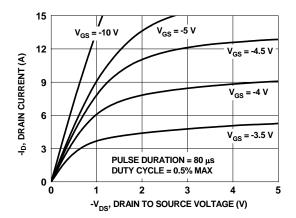


Figure 1. On-Region Characteristics

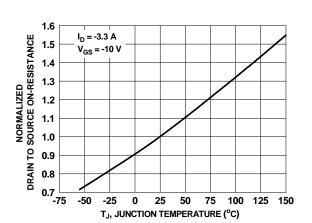


Figure 3. Normalized On-Resistance vs Junction Temperature

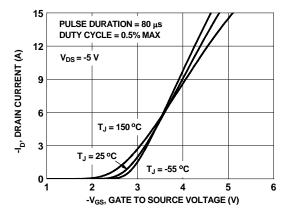


Figure 5. Transfer Characteristics

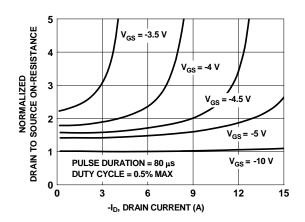


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

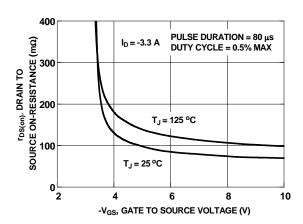


Figure 4. On-Resistance vs Gate to Source Voltage

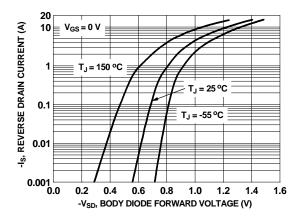


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25$ °C unless otherwise noted

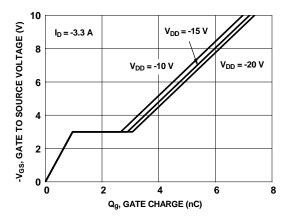


Figure 7. Gate Charge Characteristics

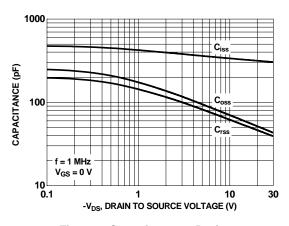


Figure 8. Capacitance vs Drain to Source Voltage

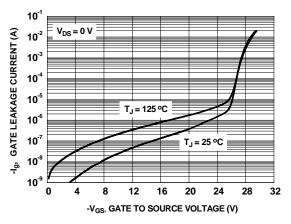


Figure 9. Gate Leakage Current vs Gate to Source Voltage

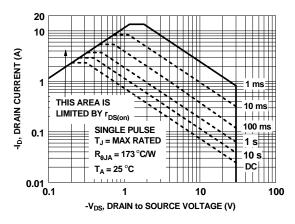


Figure 10. Forward Bias Safe Operating Area

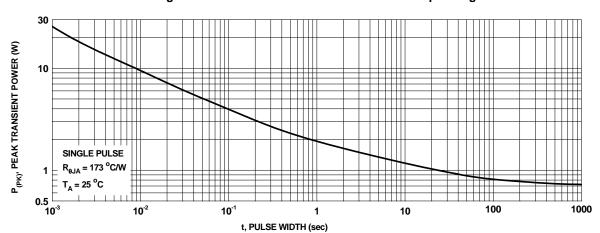


Figure 11. Single Pulse Maximum Power Dissipation



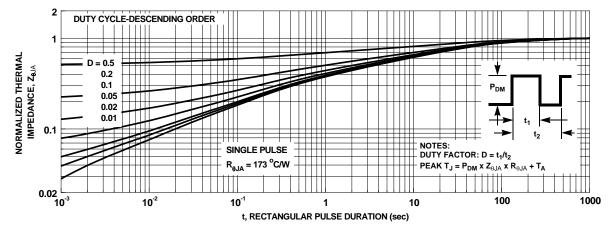
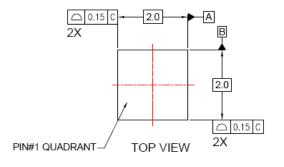
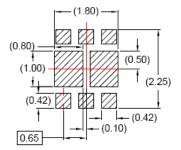


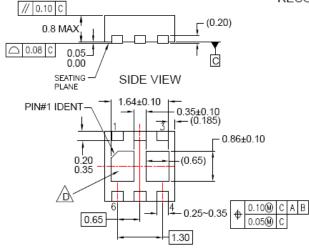
Figure 12. Junction-to-Ambient Transient Thermal Response Curve

Dimensional Outline and Pad Layout





RECOMMENDED LAND PATTERN



BOTTOM VIEW

NOTES:

- A. CONFORMS TO JEDEC REGISTRATION MO-229, VARIATION VCCC EXCEPT AS NOTED.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER

ASME Y14.5M, 1994

D. NON-JEDEC DUAL DAP





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No Identification Needed Full Production		Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

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